

July 1998

54ABT646 Octal Transceivers and Registers with TRI-STATE® Outputs

General Description

The 'ABT646 consists of bus transceiver circuits with TRI-STATE, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal registers. Data on the A or B bus will be clocked into the registers as the appropriate clock pin goes to a high logic level. Control $\overline{\text{OE}}$ and direction pins are provided to control the transceiver function. In the transceiver mode, data present at the high impedance port may be stored in either the A or the B register or in both. The select controls can multiplex stored and real-time (transparent mode) data. The direction control determines which bus will receive data when the enable control $\overline{\text{OE}}$ is Active LOW. In the B register and/or B data may be stored in the A register.

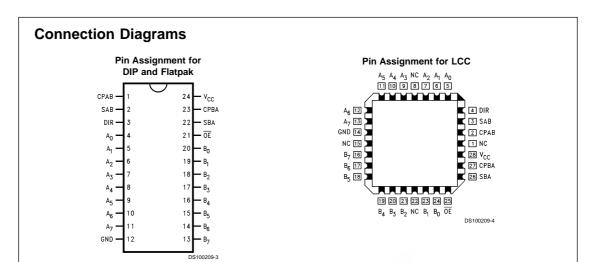
Features

- Independent registers for A and B buses
- Multiplexed real-time and stored data
- A and B output sink capability of 48 mA, source capability of 24 mA
- Guaranteed multiple output switching specifications
- Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability
- Standard Microcircuit Drawing (SMD) 5962-9457701

Ordering Code

Military	Package Number	Package Description
54ABT646J-QML	J24A	24-Lead Ceramic Dual-In-Line
54ABT646W-QML	W24C	24-Lead Cerpack
54ABT646E-QML	E28A	28-Lead Ceramic Leadless Chip Carrier, Type C

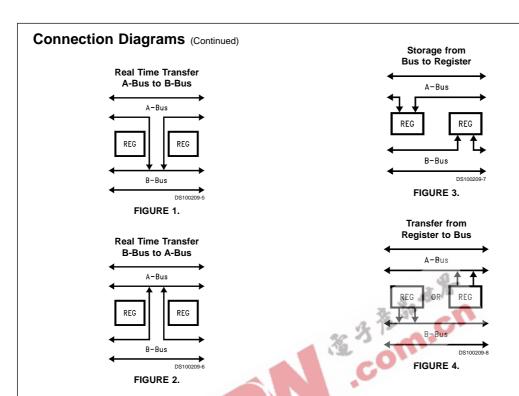
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Pin Descriptions

Pin	Description
Names	28 34
A ₀ -A ₇	Data Register A Inputs/
	TRI-STATE Outputs
B ₀ -B ₇	Data Register B Inputs/
	TRI-STATE Outputs
CPAB,	Clock Pulse Inputs
СРВА	
SAB, SBA	Select Inputs
ŌE	Output Enable Input
DIR	Direction Control Input

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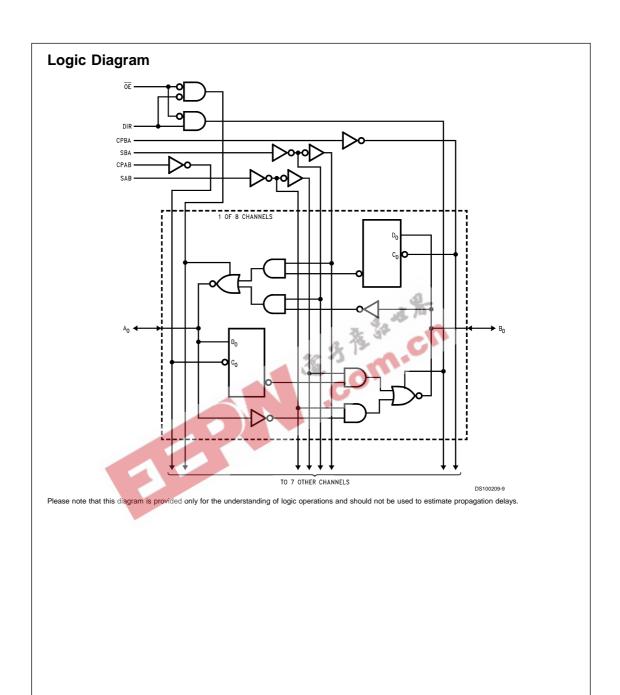


		Inp	uts				a I/O te 1)	Function
ŌĒ	DIR	CPAB	CPBA	SAB	SBA	A ₀ -A ₇ B ₀ -B ₇		
Н	Χ	H or L	H or L	X	X			Isolation
Н	Χ	~	X	X	Χ	Input	Input	Clock A _n Data into A Register
Н	Χ	Χ	-	Χ	Χ			Clock B _n Data into B Register
L	Н	Х	X	L	X			A _n to B _n —Real Time (Transparent Mode)
L	Н	~	Χ	L	Χ	Input	Output	Clock A _n Data into A Register
L	Н	H or L	Χ	Н	Χ			A Register to B _n (Stored Mode)
L	Н	~	X	Н	Χ			Clock A _n Data into A Register and Output to B _n
L	L	Х	Х	Х	L			B _n to A _n —Real Time (Transparent Mode)
L	L	Χ	~	Х	L	Output	Input	Clock B _n Data into B Register
L	L	Χ	H or L	X	Н			B Register to A _n (Stored Mode)
L	L	Х	~	Χ	Н			Clock B _n Data into B Register and Output to A _n

H = HIGH Voltage Level

Note 1: The data output functions may be enabled or disabled by various signals at the $\overline{\text{OE}}$ and DIR inputs. Data input functions are always enabled; i.e., data at the bus pins will be stored on every LOW-to-HIGH transition of the appropriate clock inputs.

L = LOW Voltage Level X = Immaterial



Absolute Maximum Ratings (Note 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Storage Temperature -65°C to +150°C -55°C to +125°C Ambient Temperature under Bias

Junction Temperature under Bias

-55°C to +175°C Ceramic V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V Input Voltage (Note 3) -0.5V to +7.0VInput Current (Note 3) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disable or

Power-Off State -0.5V to +5.5V in the HIGH State -0.5V to $\rm V_{\rm CC}$

Current Applied to Output in LOW State (Max) twice the rated I_{OL} (mA) DC Latchup Source Current

Over Voltage Latchup (I/O)

10V

Recommended Operating Conditions

Free Air Ambient Temperature

–55°C to +125°C Military

Supply Voltage

Military +4.5V to +5.5V Minimum Input Edge Rate $(\Delta V/\Delta t)$ Data Input 50 mV/ns 20 mV/ns Enable Input Clock Input 100 mV/ns

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter		ABT646		Units	V _{cc} 🦥	Conditions	
		Min	Тур	Max		31	C	
V _{IH}	Input HIGH Voltage	2.0			V	5 4)	Recognized HIGH Signal	
V _{IL}	Input LOW Voltage			0.8	V		Recognized LOW Signal	
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = −18 mA (Non I/O Pins)	
V _{OH}	Output HIGH 54ABT	2.5			V		$I_{OH} = -3 \text{ mA}, (A_n, B_n)$	
	Voltage 54ABT	2.0				Min	$I_{OH} = -24 \text{ mA}, (A_n, B_n)$	
V _{OL}	Output LOW 54ABT Voltage			0.55	V	Min	$I_{OL} = 48 \text{ mA}, (A_n, B_n)$	
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA, (Non-I/O Pins) All Other Pins Grounded	
I _{IH}	Input HIGH Current			5	μA	Max	V _{IN} = 2.7V (Non-I/O Pins) (Note 5)	
				5			V _{IN} = V _{CC} (Non-I/O Pins)	
I _{BVI}	Input HIGH Current Breakdown Test			7	μA	Max	V _{IN} = 7.0V (Non-I/O Pins)	
I _{BVIT}	Input HIGH Current Breakdown Test (I/O)			100	μA	Max	$V_{IN} = 5.5V (A_n, B_n)$	
I _{IL}	Input LOW Current			-5	μA	Max	V _{IN} = 0.5V (Non-I/O Pins) (Note 5)	
				-5			V _{IN} = 0.0V (Non-I/O Pins)	
I _{IH} + I _{OZH}	Output Leakage Current			50	μA	0V-5.5V	$V_{OUT} = 2.7V (A_n, B_n); \overline{OE} = 2.0V$	
I _{IL} + I _{OZL}	Output Leakage Current			-50	μΑ	0V-5.5V	$V_{OUT} = 0.5V (A_n, B_n); \overline{OE} = 2.0V$	
I _{os}	Output Short-Circuit Current	-100		-275	mA	Max	$V_{OUT} = 0V (A_n, B_n)$	
I _{CEX}	Output HIGH Leakage Current			50	μA	Max	$V_{OUT} = V_{CC} (A_n, B_n)$	
l _{zz}	Bus Drainage Test			100	μA	0.0V	V_{OUT} = 5.5V (A _n , B _n); All Others GND	
I _{CCH}	Power Supply Current			250	μA	Max	All Outputs HIGH	
I _{CCL}	Power Supply Current			30	mA	Max	All Outputs LOW	
I _{CCZ}	Power Supply Current			50	μA	Max	Outputs TRI-STATE; All Others GND	
I _{CCT}	Additional I _{CC} /Input			2.5	mA	Max	$V_I = V_{CC} - 2.1V$ All Other Outputs at V_{CC} or GND	
I _{CCD}	Dynamic I _{CC} No Load (Note 5)			0.18	mA/MHz	Max	Outputs Open OE and DIR = GND, Non-I/O = GND or V _{CC} (Note 4) One Bit toggling, 50% duty cycle	

-500 mA

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DC Electrical Characteristics (Continued)

Note 4: For 8-bit toggling, I_{CCD} < 1.4 mA/MHz.

Note 5: Guaranteed but not tested.

AC Electrical Characteristics

		54A	BT	Units	Fig. No.
		T _A = -55°C	to +125°C		
Symbol	Parameter	V _{CC} = 4.	5V-5.5V		
		C _L = 5	50 pF		
		Min	Max		
f _{max}	Max Clock Frequency	125		MHz	
t _{PLH}	Propagation Delay	2.2	8.8	ns	Figure 8
t _{PHL}	Clock to Bus	1.7	8.8		
t _{PLH}	Propagation Delay	1.5	7.9	ns	Figure 8
t _{PHL}	Bus to Bus	1.5	7.9		
t _{PLH}	Propagation Delay	1.5	8.1	ns	Figure 8
t _{PHL}	SBA or SAB to A _n to B _n	1.5	8.9		
t _{PZH}	Enable Time	1.0	7.3	ns	Figure 10
t _{PZL}	\overline{OE} to A_n or B_n	1.9	8.8		
t _{PHZ}	Disable Time	1.5	9.3	ns	Figure 10
t _{PLZ}	\overline{OE} to A_n or B_n	1.5	9.3		
t _{PZH}	Enable Time	1.0	7.7	ns	Figure 10
t _{PZL}	DIR to A _n or B _n	2.2	9.5		
t _{PHZ}	Disable Time	1.5	8.7	ns	Figure 10
t_{PLZ}	DIR to A _n or B _n	1.5	9.2		

AC Operating Requirements

Symbol	Parameter	54ABT T _A = -55°C to +125°C V _{CC} = 4.5V-5.5V C _L = 50 pF		Units	Fig. No.
		Min	Max		
t _S (H)	Setup Time, HIGH	3.5		ns	Figure 11
t _S (L)	or LOW Bus to Clock				
t _H (H)	Hold Time, HIGH	1.0		ns	Figure 11
$t_H(L)$	or LOW Bus to Clock				
t _W (H)	Pulse Width,	4.0		ns	Figure 9
$t_W(L)$	HIGH or LOW				

Capacitance

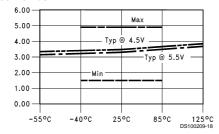
Symbol	Parameter	Тур	Units	Conditions T _A = 25°C
C _{IN}	Input Capacitance	5	pF	V _{CC} = 0V (non I/O pins)
C _{I/O} (Note 6)	Output Capacitance	11	pF	$V_{CC} = 5.0V (A_n, B_n)$

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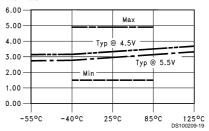
Note 6: $C_{I/O}$ is measured at frequency, f = 1 MHz, per MIL-STD-883B, Method 3012.

Capacitance (Continued)

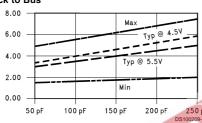
 $t_{\rm PLH}$ vs Temperature (T_A) C_L = 50 pF, 1 Output Switching Clock to Bus



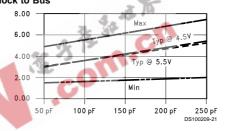
 t_{PHL} vs Temperature (T_A) C_L = 50 pF, 1 Output Switching Clock to Bus



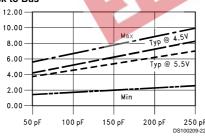
t_{PLH} vs Load Capacitance 1 Output Switching, T_A = 25°C Clock to Bus



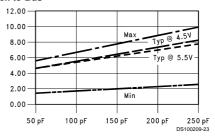
t_{PHL} vs Load Capacitance 1 Output Switching, T_A = 25°C Clock to Bus



t_{PLH} vs Load Capacitance 8 Outputs Switching, T_A = 25°C Clock to Bus



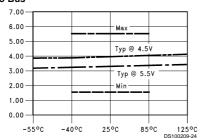
t_{PHL} vs Load Capacitance 8 Outputs Switching, T_A = 25°C Clock to Bus



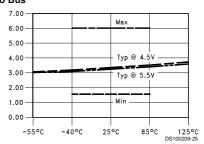
Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.

Capacitance (Continued)

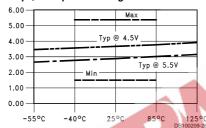
 t_{PZL} vs Temperature (T_A) $\underline{C_L}$ = 50 pF, 1 Output Switching OE to Bus



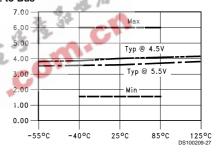
 t_{PLZ} vs Temperature (T_A) $\underline{\text{C}_{\text{L}}}$ = 50 pF, 1 Output Switching OE to Bus



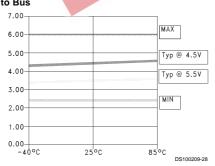
 t_{PZH} vs Temperature (T_A) C_L = 50 pF, 1 Output Switching



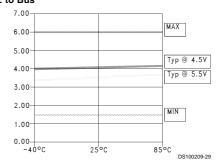
 t_{PHZ} vs Temperature (T_A) $\underline{C_L}$ = 50 pF, 1 Output Switching OE to Bus



t_{PZH} vs Temperature (T_A)
C_L = 50 pF, 8 Outputs Switching
OE to Bus



 t_{PHZ} vs Temperature (T_A) $\underline{C_L}$ = 50 pF, 8 Outputs Switching OE to Bus

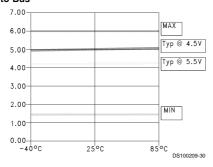


Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.

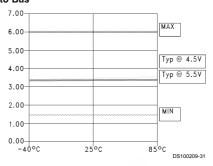
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Capacitance (Continued)

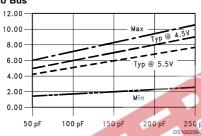
t_{PZL} vs Temperature (T_A) $\underline{C_L}$ = 50 pF, 8 Outputs Switching OE to Bus



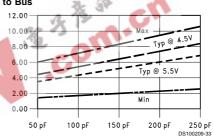
$t_{\rm PLZ}$ vs Temperature (T_A) $\underline{C_{\rm L}}$ = 50 pF, 8 Outputs Switching OE to Bus



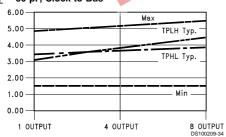
t_{PZL} vs Load Capacitance <u>8 Outputs Switching</u>, T_A = 25°C OE to Bus



t_{PZH} vs Load Capacitance <u>8 Outputs Switching</u>, T_A = 25°C OE to Bus



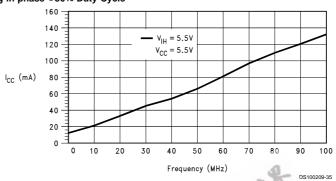
 t_{PLH} and t_{PHL} vs Number Output Switching $V_{CC} = 5.0V$, $T_A = 25^{\circ}C$ $C_L = 50$ pF, Clock to Bus



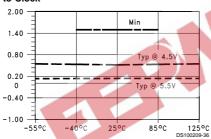
Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.

Capacitance (Continued) I_{CC} vs Frequency, Average, T_A = 25°C, V_{CC} = 5.5V All Outputs Unloaded/Unterminated;

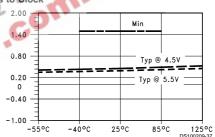
All Outputs Switching in phase @50% Duty Cycle



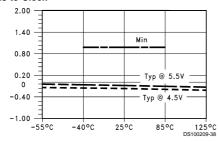
 t_{SET} LOW vs Temperature (T_A) C_L = 50 pF, 1 Output Switching Bus to Clock



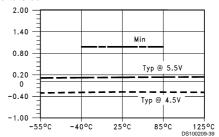
t_{SET} HIGH vs Temperature (T_A) C_L = 50 pF, 1 Output Switching Bus to Clock



t_{HOLD} LOW vs Temperature (T_A) C_L = 50 pF, 1 Output Switching Bus to Clock



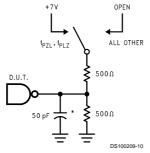
 t_{HOLD} HIGH vs Temperature (T_A) $C_L = 50$ pF, 1 Output Switching Bus to Clock



Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Tables.

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AC Loading



*Includes jig and probe capacitance

FIGURE 5. Standard AC Test Load

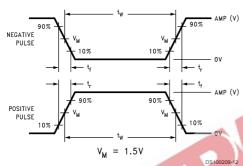


FIGURE 6. Test Input Signal Levels
Input Pulse Requirements

Amplitude	Rep. Rate	t _W	t _r	t _f
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 7. Test Input Signal Requirements

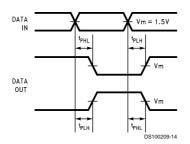


FIGURE 8. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

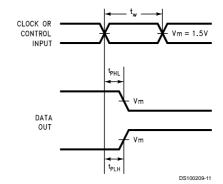


FIGURE 9. Propagation Delay, Pulse Width Waveforms

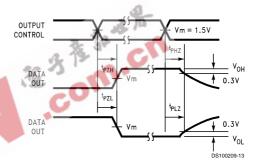


FIGURE 10. TRI-STATE Output HIGH and LOW Enable and Disable Times

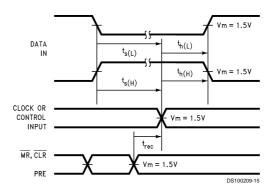
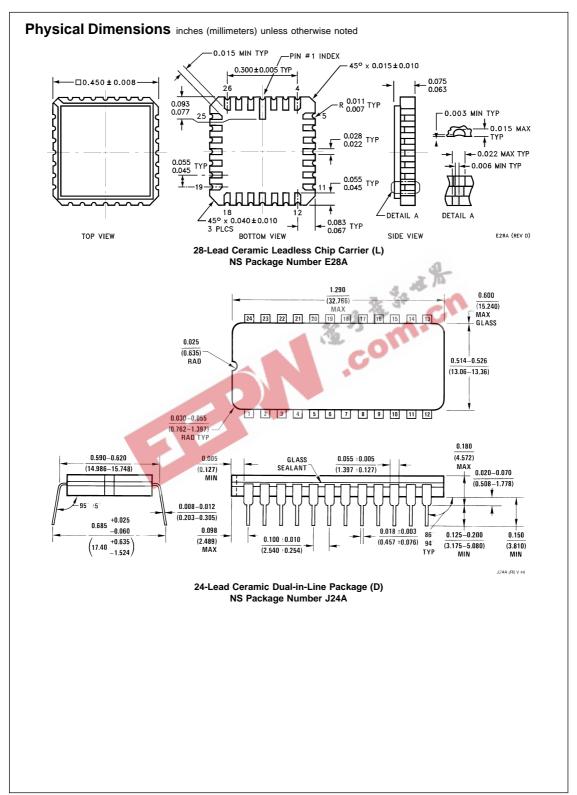


FIGURE 11. Setup Time, Hold Time and Recovery Time Waveforms





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Physical Dimensions inches (millimeters) unless otherwise noted (Continued) 0.625 0.590 0.040 0.050 ± 0.005 0.005 MIN TYP 0.030 0.370 0.250 0.015 0.019 0.015 0.420 MAX 0.370 SFF DETAIL A 0.006 - 0.045 MA W24C (REV E) 24-Lead Ceramic Flatpak Package (F) NS Package Number W24C .com.

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